Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/889,317	TRIPP ET AL.
Examiner	Art Unit
F. Pierre VanderVegt	1644

SEARCHED				
Class	Subclass	Date	Examiner	
424	130.1 133.1	4/5/2006	PV	
530	387.1			
	388.24			
	389.2			
<b>-</b>				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
424	130.1	4/5/2006	100 m		
424	133.1				
530	387.1				
530   388,24, 389.2					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST STN Updated	4/5/2006	a/		
Allowability Conference David Saunders -Primary Examiner. Christina Chan - SPE	4/6/2006	R		
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